12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20180628002.1
Qualification of MIHO8 as an additional Fab site option for select ABCD5HV devices
Change Notification / Sample Request

Date: July 03, 2018
To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN_ww_admin_team@list.ti.com).

PCN Team
SC Business Services

20180628002.1
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
TCAN1042HVDR	null
TCAN1042HD	null
TCAN1042HDR	null
TCAN1042HGD	null
TCAN1051HGD	null

Technical details of this Product Change follow on the next page(s).

PCN Number:	20180628002.1	**PCN Date:**	July 3, 2018
Title:	Qualification of MIHO8 as an additional Fab site option for select ABCD5HV devices		
Customer Contact:	PCN Manager	**Dept:**	Quality Services
Proposed 1st Ship Date:	Oct 3, 2018	**Estimated Sample Availability:**	Date provided at sample request.

Change Type:

☐	Assembly Site	☐	Assembly Process	☐	Assembly Materials
☐	Design	☐	Electrical Specification	☐	Mechanical Specification
☐	Test Site	☐	Packing/Shipping/Labeling	☐	Test Process
☐	Wafer Bump Site	☐	Wafer Bump Material	☐	Wafer Bump Process
☒	Wafer Fab Site	☐	Wafer Fab Materials	☐	Wafer Fab Process
		☐	Part number change		

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its MIHO8 fabrication facility as an additional Wafer Fab source for the selected devices listed in the "Product Affected" section.

Current Fab Site			Additional Fab Site		
Current Fab Site	**Process**	**Wafer Diameter**	**Additional Fab Site**	**Process**	**Wafer Diameter**
MAINEFAB	ABCD5HV	200 mm	MIHO8	ABCD5HV	200 mm

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current:

Current Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
MAINEFAB	CUA	USA	South Portland

New Fab Site:

New Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
MIHO8	**MH8**	**JPN**	**Ibaraki**

Sample product shipping label (not actual product label)

Product Affected:

TCAN1042HD	TCAN1042HGVD	TCAN1051HD	TCAN1051HGVD
TCAN1042HDR	TCAN1042HGVDR	TCAN1051HDR	TCAN1051HGVDR
TCAN1042HGD	TCAN1042HVD	TCAN1051HGD	TCAN1051HVD
TCAN1042HGDR	TCAN1042HVDR	TCAN1051HGDR	TCAN1051HVDR

Qualification Report

ABCD05HV in Miho8
Approve Date 23-Jun-2018

Product Attributes

Attributes	Qual Device: TCAN1042HVDRQ1	Qual Device: TCAN1051VDRQ1
Assembly Site	FMX	FMX
Package Family	SOIC	SOIC
Flammability Rating	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	MIHO8	MIHO8
Wafer Fab Process	ABCD05HV.3	ABCD05HV.3

- QBS: Qual By Similarity
- Qual Devices TCAN1042HVDRQ1 and TCAN1051VDRQ1 are qualified at LEVEL1-260C

Qualification Results
Data Displayed as: Number of lots / Total sample size / Total failed

	Type	Test Name / Condition	Duration	Qual Device: TCAN1042HVDRQ1	Qual Device: TCAN1051VDRQ1
	AC	Autoclave 121C	96 Hours	2/154/0	1/77/0
	CDM	ESD - CDM	1500 V	2/6/0	1/3/0
	ED	Electrical Distributions	Per Datasheet Parameters	3/90/0	3/90/0
	ELFR	Early Life Failure Rate, 125C	48 Hours	2/1600/0	1/800/0
	HAST	Biased HAST, 130C/85%RH	96 Hours	2/154/0	1/77/0
	HBM	ESD - HBM	6000 V	1/3/0	1/3/0
	HBM	ESD - HBM (Bus Pins Only)	16000 V	2/6/0	1/3/0
	HTOL	Life Test, 150C	300 Hours	2/153/0	1/77/0
	HTSL	High Temp Storage Bake 175C	500 Hours	2/90/0	1/45/0
	LU	Latch-up	(Per JESD78)	2/12/0	1/6/0
	TC	Temperature Cycle, -65/150C	500 Cycles	2/154/0	1/77/0
	WBP	Bond Pull	Wires	2/60/0	-
	WBS	Wire Bond Shear	Wires	2/60/0	1/30/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:
Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com